NISTTech

PROBE MODULE, METHOD FOR MAKING AND USE OF SAME

Docket No. 13-025

Applications

- **Spectroscopy**
  Can be used for Contact Resonance Spectroscopy
- **Spectroscopy**
  Can be used for Force Distance Spectroscopy
- **Microscopy**
  Can be used for Dynamic Lateral force microscopy

Advantages

- **Multi-Electrode arrays**
  Multi-electrode arrays enable new measurement modes for AFM
- **Comercially available tips**
  Modular electrostatic actuator for a wide range of commercially available tips
- **Compatabile**
  compatible with most commercially-available cantilevers

Abstract

Displacement control of AFM (atomic force microscope) cantilevers has previously be implemented using different forms of actuation and probes. This invention is in regard to electrostatic actuation. The invention is an apparatus for electrostatic actuation using a new design for a cantilever chip holder that is compatible with optical lever based AFM. This new design allows the AFM advantages in several areas over state of the art of electrostatic actuation in an AFM.

Inventors

- Cannara, Rachel
- Long, Christian

References

- US Patent No. 8,943,611

Status of Availability

This invention is available for licensing exclusively or non-exclusively in any field of use.

Last Modified: 05/29/2015